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Thu, 20 Dec	16:15 — 17:50	TEST	Management and Marketing  Silenko A.N.  A-100
Mon, 24 Dec	09:00 — 12:00	ATT	Sensors Based on Micro- and Nanotechnologies  Podlepetskiy B.I.  V-411
Mon, 24 Dec	12:00 — 15:00	ATT	Software Support of Modern Microprocessors and Microcontrollers  Shagurin I.I.  D-311
Tue, 25 Dec	09:00 — 12:00	TEST	Life Safety  Hayretdinov S.I.  E-214
Tue, 25 Dec	12:00 — 15:00	TEST	Microelectronic Radio Devices  Bocharov Y.I.  D-311
Thu, 27 Dec	09:00 — 12:00	ATT	Reliability and Radiation Resistance of Integrated Circuits  Zebrev G.I.  D-303
Thu, 27 Dec	12:00 — 15:00	TEST	Quantum Radiophysics  Larkin A.I.  K-1117
Fri, 28 Dec	09:00 — 12:00	TEST	Information Measurement Systems  Belyakov V.V.  D-311
Fri, 28 Dec	12:00 — 15:00	TEST	Scientific Research Work  Shagurin I.I.  dep.27
Fri, 28 Dec	15:00 — 18:00	ATT	Principles of Optoelectronics  Voronov Y.A.  402
Thu, 10 Jan	09:00 — 13:00	EXAM	Software Support of Modern Microprocessors and Microcontrollers  Shagurin I.I.  T-102
Mon, 14 Jan	09:00 — 13:00	EXAM	Sensors Based on Micro- and Nanotechnologies  Podlepetskiy B.I.  T-102
Sat, 19 Jan	09:00 — 13:00	EXAM	Principles of Optoelectronics  Voronov Y.A.  V-417
Thu, 24 Jan	09:00 — 13:00	EXAM	Reliability and Radiation Resistance of Integrated Circuits  Zebrev G.I.  D-311